



The preparation and antiferromagnetic properties of epitaxial rocksalt-type CoN films



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ABSTRACT

We have grown epitaxial rocksalt-type CoN films on SrTiO₃ and sapphire substrates by ablating a cobalt target in activated nitrogen atmosphere. The structural and magnetic properties have been investigated. X-ray diffraction profiles show CoN films grow along the [100] and [111] direction on SrTiO₃(100) and α -Al₂O₃(0001), respectively. High-resolution transmission electron microscopy measurement has been performed on CoN/SrTiO₃ system, which shows a good epitaxial growth. Temperature-dependent magnetization curves reveal that the as-grown films have antiferromagnetic properties with T_N of \sim 310 K.

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The preparation and the basic magnetic properties of magnetic transition metal nitrides MN_x (M = Cr, Mn, Fe, Co, Ni) have attracted increasing attention in recent years, due to the potential application in high density magnetic recording media [1]. To date, the research on FeN_x, MnN_x, CrN_x, and NiN_x has been reported widely [2–5], whereas the study of CoN_x is relatively poor. To the best of our knowledge, although a limited number of publications have reported various phases of Co–N system such as Co₄N, Co₃N, Co₂N, Co₂N₃, and CoN, [6–10] the detailed magnetic measurements are still scarce. For example, the perovskite structure Co₄N is found to be ferromagnetic (FM) in nature, but the exact value of Curie temperature (T_C) remains unclear. With regard to Co₂N and Co₃N, the related magnetic measurements are waiting to be developed. AB-type structure is a common phase of 3d transition metal nitrides. Cobalt mononitride (CoN) has two possible crystal structures: rocksalt (RS-) type and zinc-blende (ZB-) type. An earlier work about CoN is reported by Schmitz-Dumont et al. who prepared RS-type CoN powder by the thermal decomposition of cobalt(III) amide Co(NH₂)₃, and found it had RS-type structure [11]. The relevant physical properties are very hard to be referred. Recently, Suzuki et al. prepared the ZB-type polycrystalline CoN film by d.c. reactive sputtering, magnetic measurements and nuclear magnetic resonance demonstrated it exhibited Pauli paramagnetic character [12,13].

In our opinion, the difficult obtainment of high quality Co–N films is the main factor that hinders the related research. Because CoN_x can stable into a wide range x , CoN_x films often comprise

more than one phase [14,15]. Only a few works report the pure phase CoN_x films prepared by magnetron sputtering, molecular beam epitaxy, and nitridation of Co film [12,16,8]. In the present work, we report laser molecular beam epitaxy (Laser-MBE) is an effective way to get CoN single crystal film. The films show typical antiferromagnetic (AFM) nature with a Néel temperature (T_N) of \sim 310 K. The magnetic property suggests the prepared CoN films have RS-type structure rather than ZB-type.

RS-type cobalt mononitride films were grown on SrTiO₃(100) and α -Al₂O₃(0001) substrates by means of Laser-MBE with a XeCl excimer laser (wavelength = 308 nm, repetition = 2 Hz, and energy density = 1.5 J/cm²). [17] A high-purity cobalt disk (purity >99.99%) was employed as target. Before deposition, gas pipes and epitaxy chamber had been carefully cleaned using high-purity N₂ (>99.999%). The epitaxy chamber was pumped to 10^{–6} Pa before nitrogen gas was introduced into the chamber, and nitrogen partial pressure was kept at 0.5 Pa. The nitrogen had been activated by a home-made glowing discharge unit and been sprayed to the substrate surface directly. The substrate temperature during the growth was maintained at 370 °C after excluding other temperature prudently. The nitrogen source was turn off after the samples were cooled down to 150 °C. The growth time was 4 h, and growth rate was estimated to be 3.3 Å/min. The thicknesses of grown films were about 80 nm.

The surface quality was monitored by *in situ* reflection high energy electron diffraction (RHEED). And the RHEED patterns were recorded after the growth. Fig. 1a and b shows two RHEED patterns of as-grown CoN film on SrTiO₃ substrate, in which the incident electron beam is parallel to SrTiO₃ [110] and [100] direction, respectively. The bright and sharp diffraction streaks indicate the

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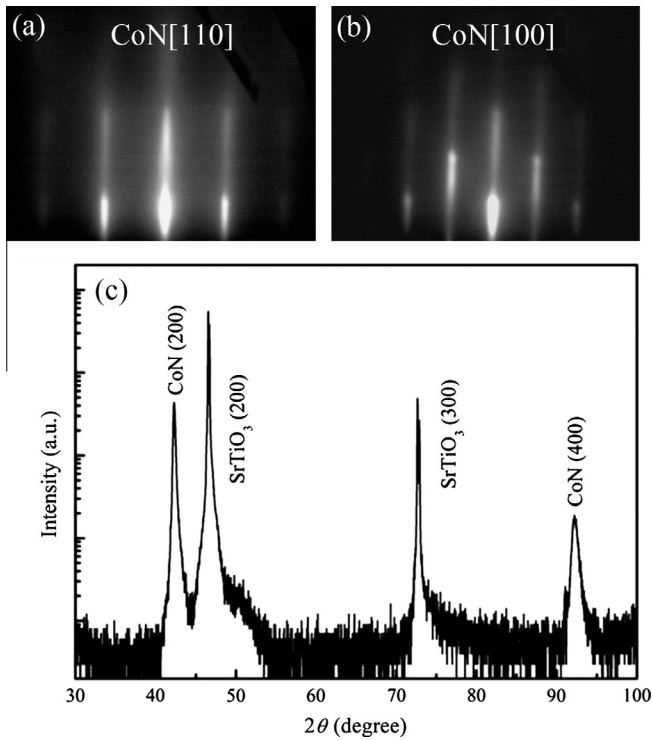


Fig. 1. (a) and (b) show RHEED patterns of as-grown CoN film on SrTiO₃ substrate, in which the incident electron beam is along SrTiO₃ [1 1 0] and [1 0 0] direction. (c) A typical θ - 2θ scanning X-ray diffraction profile of CoN film on SrTiO₃(100).

well crystallization. But the extra spots on the streaks suggest slightly rough surface. It is noted that both RHEED patterns turn up again after rotating the substrate by 90°. The crystal structure was characterized by X-ray diffraction (XRD) using Rigaku D/Max-2400 with Cu K α radiation. Fig. 1c displays a typical XRD θ - 2θ scanning curve of CoN film on SrTiO₃ substrate. With the exception of two peaks ascribed to substrate, only diffraction peaks at $2\theta = 42.3^\circ$ and 92.25° associated with CoN (200) and (400) were detected, without any diffraction signal from either randomly oriented grain or impurity phase, revealing the as-grown CoN films have highly pure crystal phase and grow along [100] direction on SrTiO₃(100) substrate. Using Bragg formula, the crystal constant of CoN is estimated to be $a = 4.27 \text{ \AA}$. This is in accord with the value of RS-type CoN powder reported in Ref. [11]. Based on the RHEED and XRD results, we can speculate that the epitaxial relationship between CoN and SrTiO₃ is a cube-on-cube type even the lattice mismatch is as high as $[a(\text{CoN})-a(\text{STO})]/a(\text{STO}) \times 100\% = 9.3\%$.

As mentioned previously, we know cubic CoN has two possible crystal structures: zinc-blende (ZB) type and rocksalt (RS) type. They have similar lattice constants (4.28 \AA for ZB-type and 4.27 \AA for RS-type) [12]. In both of these structures, Co atoms arrange into a face-centered cubic (f.c.c.) structure. The only difference is the arrangement of nitrogen atoms. So it is difficult to exactly point out the phase of the as-grown films only by θ - 2θ profile. A general but nonstrict method to distinguish the two structures is to compare the relative intensity of diffraction peaks in XRD profiles due to the different structure factors [12]. But in here, this method is impracticable because the diffraction just takes place from a single crystal plane. Therefore, other measurements are highly required to identify the film structure.

To analyze the microstructures of CoN(100)/SrTiO₃(100) system, high-resolution transmission electron microscopy (HRTEM) measurements were performed to the cross section using a FEI Tecnai G2 F20 microscope. (Fig. 2a) presents a cross-sectional HRTEM

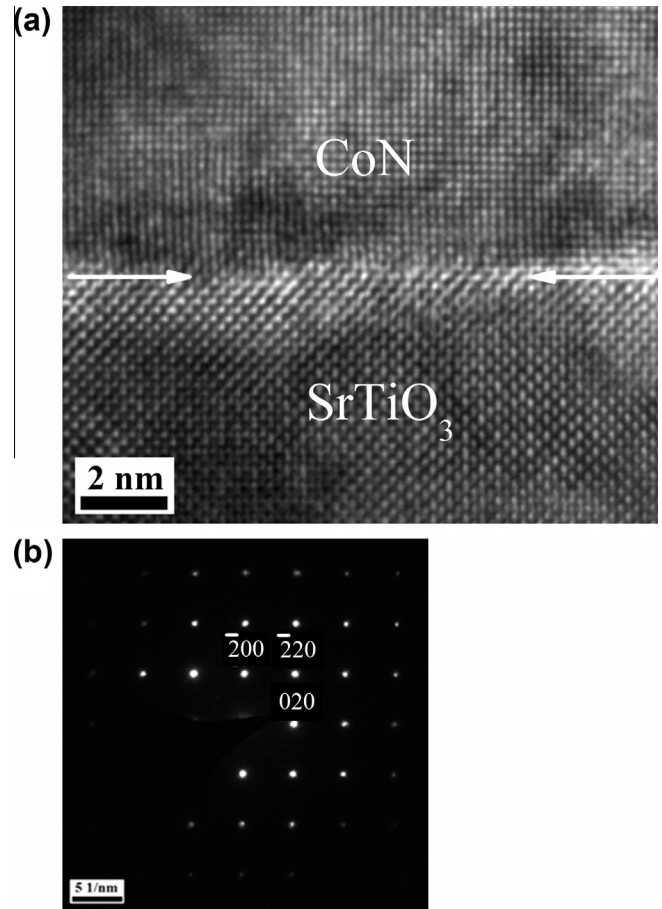


Fig. 2. (a) High-resolution cross-sectional TEM image of CoN/SrTiO₃ film. (b) The SAED pattern of CoN film.

image of CoN/SrTiO₃. The interface of film/substrate is very clear and the atomic arrangement is highly ordered in the film part, which are indicative of epitaxial growth. Because of the large lattice mismatch (9.3%), several atom layers closing to the interface have to adopt distortion to achieve the epitaxial growth. The selected-area electron diffraction (SAED) pattern (in Fig. 2b) shows a very clean single crystal diffraction pattern, revealing that the as-grown CoN film has well single crystal structure, it is in good agreement with XRD measurement. The film is indexed to be a cubic structure.

Magnetic measurements were carried out with a vibrating sample magnetometer (VSM, PPMS-9T). Zero-field-cooled (ZFC) and field-cooled (FC) d.c. magnetization measured in a temperature range of 10–400 K are plotted in Fig. 3a. External field of 0.2 and 10 kOe were applied in the plane of the film. It is very clear that each thermomagnetic (M - T) curves shows a sharp peak at the temperature of $T \sim 310 \text{ K}$. We tentatively speculate that CoN film transits from high-temperature paramagnetic (PM) order to low-temperature AFM order with a Néel point of $T = 310 \text{ K}$. In fact, at $T \geq 310 \text{ K}$, the magnetizations increase gradually with the decreasing temperature, and behave in Curie-Weiss law for $1/M$ show linear temperature dependence approximately, as plotted in the inset of Fig. 3a, which is a typical characteristic for PM materials. At $T < 310 \text{ K}$, the magnetizations decrease with the reducing temperature, the film transits into AFM state. It is should be noted that ZB-type CoN is Pauli paramagnetic, which is verified by nuclear magnetic resonance and magnetization measurements [12,13]. In addition, a lot of works show RS-type mononitrides of the neighboring elements of cobalt, such as CrN, MnN, FeN have typical AFM

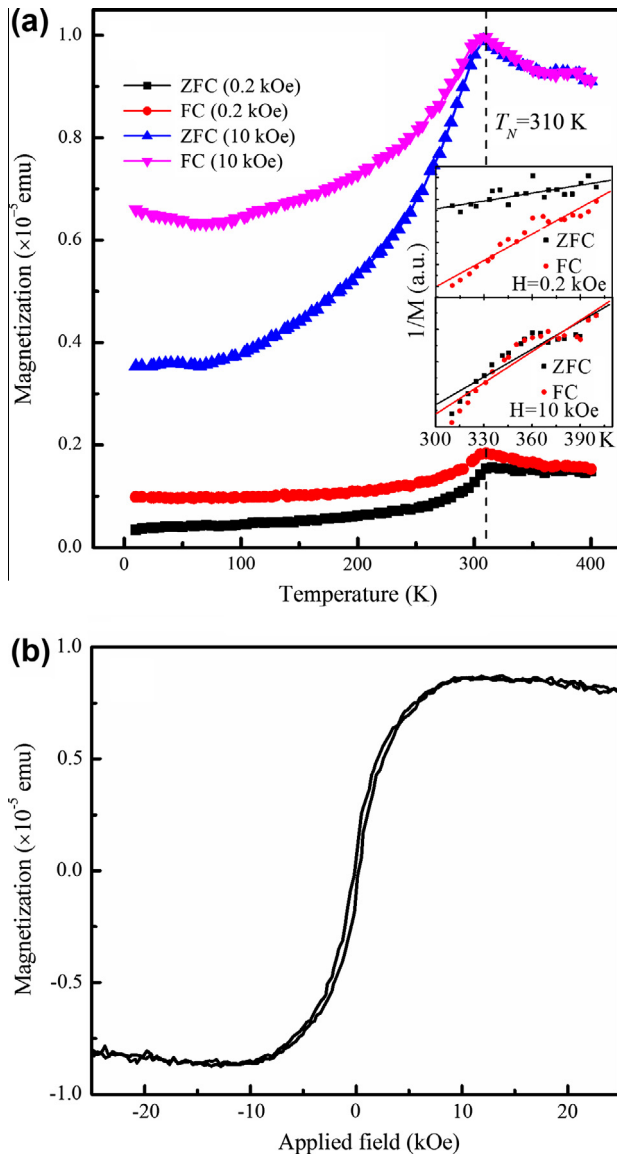


Fig. 3. (a) ZFC and FC magnetization of CoN(100)/SrTiO₃(100) from 10 to 400 K measured at 0.2 and 10 kOe field. The insets show the value of $1/M$ in the temperature range of 310–400 K, solid lines are fitting results by Curie–Weiss law. (b) M – H loop of CoN(100)/SrTiO₃(100) measured at 300 K.

properties [18–20]. Phase transition is one of the most important intrinsic characteristics of a material. Therefore, we can conclude that the as-prepared CoN films should not be ZB-type structure, but be RS-type structure because of their AFM property.

The field-dependent magnetization (M – H) loop is plotted in Fig. 3b measured at 300 K, with an applied field parallel to the film plane. One can see a very weak ferromagnetic-like magnetic hysteresis. We tentatively ascribe it to the interfacial structures, or ferromagnetic defects, such as Co₄N and α -Co. It is more likely to form nonstoichiometric CoN_x clusters during the growth process due to the partial uncompleted nitridation.

CoN films have also been grown on c -plane sapphire substrates under the same conditions as grown on SrTiO₃ substrates. Fig. 4 plots a θ – 2θ XRD profile of CoN/Al₂O₃ system. The film shows two peaks at $2\theta = 36.6^\circ$ and 77.7° corresponding to (111) and (222) of cubic CoN. No other peak is observed, indicating that CoN film orients in [111] direction when grows on α -Al₂O₃(0001) substrate.

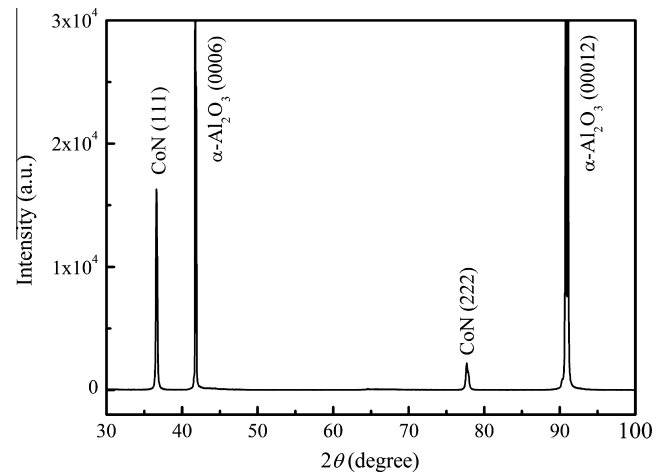


Fig. 4. A θ – 2θ scanning X-ray diffraction profile of CoN(111) film on α -Al₂O₃(0001).

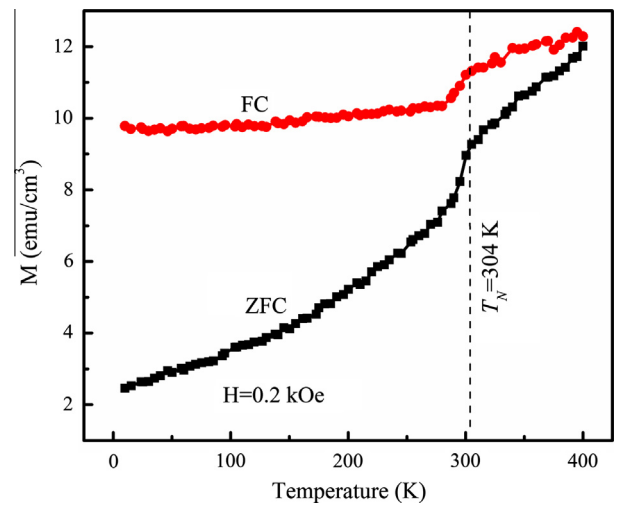


Fig. 5. Temperature-dependent magnetization curves of CoN(111)/ α -Al₂O₃(0001) measured at 0.2 kOe field.

Fig. 5 shows ZFC and FC M – T curves of CoN(111) film on α -Al₂O₃(0001) substrate measured from 10 to 400 K, with a 0.2 kOe field along the film plane. Unlike CoN/SrTiO₃ system, sharp peaks have not been observed on the M – T curves. One can see the magnetization decreases monotonously with the reducing temperature, but an obvious hop appears at $T = 304$ K on every M – T curve which corresponds to the Néel point. At $T > 304$ K, it is very clear that the magnetization does not obey the Curie–Weiss law. We attribute the anomalous phenomenon to the different interface strain, different crystal direction, and crystal defects.

In conclusion, cubic RS-type CoN epitaxial films have been grown on SrTiO₃(100) and α -Al₂O₃(0001) substrates by Laser-MBE with activated nitrogen. RHEED, XRD, and HRTEM measurements have been employed to characterize the structure of CoN(100) films grown on SrTiO₃(100). These results confirm the good crystal quality and well epitaxial growth of CoN(100) films. Magnetic measurement indicates a PM-to-AFM transition takes place at $T_N \sim 310$ K. This property suggests the as-prepared films are not Pauli paramagnetic ZB-type CoN, but AFM RS-type structure. However, the interface structures and defects may lead to the ferromagnetic-like hysteresis phenomenon. CoN film grows on α -Al₂O₃(0001) is in the [111] direction, and its AFM order temperature is ~ 304 K.

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